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# (54) METHOD FOR AT-SPEED TESTING OF MEMORY INTERFACE USING SCAN

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- (51) Int. Cl. G11C 29/00 (2006.01)

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#### (57) ABSTRACT

A method and a circuit of testing of a memory interface associated with an embedded memory in a semiconductor circuit involves writing to two memory locations in succession; reading the two memory locations in succession in the same order in which the two memory locations were written; capturing output data from the memory interface; and analyzing captured output data to determine whether said captured output data corresponds to expected data.

#### 27 Claims, 9 Drawing Sheets

